









CDCLVP1102

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CDCLVP1102 Two-LVPECL Output, High-Performance Clock Buffer

1 Features

- 1:2 Differential Buffer
- Single Clock Input
- Universal Inputs Can Accept LVPECL, LVDS, LVCMOS/LVTTL
- Two LVPECL Outputs
- Maximum Clock Frequency: 2 GHz
- Maximum Core Current Consumption: 33 mA
- Very Low Additive Jitter: <100 fs, RMS in 10-kHz to 20-MHz Offset Range
- 2.375-V to 3.6-V Device Power Supply
- Maximum Propagation Delay: 450 ps
- Maximum Output Skew: 10 ps
- LVPECL Reference Voltage, V_{AC_REF}, Available for Capacitive-Coupled Inputs
- Industrial Temperature Range: –40°C to 85°C
- Supports 105°C PCB Temperature (Measured at Thermal Pad)
- Available in 3-mm × 3-mm QFN-16 (RGT) Package
- ESD Protection Exceeds 2 kV (HBM)

2 Applications

- Wireless Communications
- Telecommunications/Networking
- Medical Imaging
- Test and Measurement Equipment

3 Description

Tools &

Software

The CDCLVP1102 is a highly versatile, low additive jitter buffer that can generate two copies of LVPECL clock outputs from one LVPECL, LVDS, or LVCMOS input for a variety of communication applications. It has a maximum clock frequency up to 2 GHz. The overall additive jitter performance is less than 0.1 ps, RMS from 10 kHz to 20 MHz, and overall output skew is as low as 10 ps, making the device a perfect choice for use in demanding applications.

The CDCLVP1102 clock buffer distributes a single clock input (IN) to two pairs of differential LVPECL clock outputs (OUT0, OUT1) with minimum skew for clock distribution. The inputs can be LVPECL, LVDS, or LVCMOS/LVTTL.

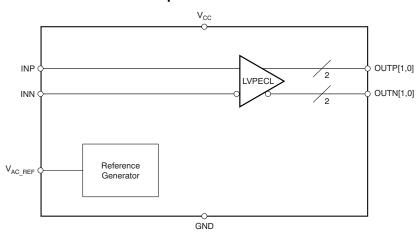
The CDCLVP1102 is specifically designed for driving 50- Ω transmission lines. When driving the inputs in single-ended mode, the LVPECL bias voltage (V_{AC_REF}) should be applied to the unused negative input pin. However, for high-speed performance up to 2 GHz, differential mode is strongly recommended.

The CDCLVP1102 is characterized for operation from -40° C to 85°C and is available in a QFN-16, 3-mm x 3-mm package.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
CDCLVP1102	QFN (16)	3.00 mm × 3.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Simplified Schematic

Product Folder Links: CDCLVP1102

Table of Contents

1	Feat	tures 1
2	Арр	lications 1
3	Des	cription 1
4	Rev	ision History 2
5	Pin	Configuration and Functions 3
6	Spe	cifications 4
	6.1	Absolute Maximum Ratings 4
	6.2	ESD Ratings 4
	6.3	Recommended Operating Conditions 4
	6.4	Thermal Information 4
	6.5	Electrical Characteristics: LVCMOS Input 5
	6.6	Electrical Characteristics: Differential Input 5
	6.7	Electrical Characteristics: LVPECL Output 6
	6.8	Electrical Characteristics: LVPECL Output7
	6.9	Typical Characteristics 8
7	Para	ameter Measurement Information
	7.1	Test Configurations9
8	Deta	ailed Description 12
	8.1	Overview 12

	8.2	Functional Block Diagram	12
	8.3	Feature Description	12
	8.4	Device Functional Modes	12
9	Appl	ication and Implementation	17
	9.1	Application Information	17
	9.2	Typical Application	17
10	Pow	er Supply Recommendations	19
11	Layo	out	20
	11.1	Layout Guidelines	20
		Layout Example	
	11.3	Thermal Considerations	20
12	Devi	ice and Documentation Support	21
	12.1	Documentation Support	21
	12.2	Community Resources	21
	12.3	Trademarks	21
	12.4	Electrostatic Discharge Caution	<mark>21</mark>
	12.5	Glossary	21
13		hanical, Packaging, and Orderable	
	Infor	mation	21

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision C (January 2011) to Revision D

•	Added support for 105°C thermal pad temperature 1
•	Added Device Information and Pin Configuration and Functions sections, ESD Rating table, Feature Description, Device Functional Modes, Application and Implementation, Power Supply Recommendations, Layout, Device and Documentation Support, and Mechanical, Packaging, and Orderable Information sections
•	Added V_{OH} specification for $T_{PCB} \le 105^{\circ}$ C in Electrical Characteristics: LVPECL Output, at $V_{CC} = 2.375$ V to 2.625 V 6
•	Added V_{OL} specification for $T_{PCB} \le 105^{\circ}$ C in Electrical Characteristics: LVPECL Output, at $V_{CC} = 2.375$ V to 2.625 V 6
•	Added I _{EE} specification for $T_{PCB} \le 105^{\circ}C$ in Electrical Characteristics: LVPECL Output, at $V_{CC} = 2.375$ V to 2.625 V 6
•	Added I_{CC} specification for $T_{PCB} \le 105^{\circ}C$ in Electrical Characteristics: LVPECL Output, at $V_{CC} = 2.375$ V to 2.625 V 6
•	Added V_{OH} specification for $T_{PCB} \le 105^{\circ}$ C in Electrical Characteristics: LVPECL Output, at $V_{CC} = 3 \text{ V to } 3.6 \text{ V}$
•	Added V_{OL} specification for $T_{PCB} \le 105^{\circ}$ C in Electrical Characteristics: LVPECL Output, at $V_{CC} = 3$ V to 3.6 V
•	Added I_{EE} specification for $T_{PCB} \le 105^{\circ}C$ in Electrical Characteristics: LVPECL Output, at $V_{CC} = 3 \text{ V to } 3.6 \text{ V}$
•	Added I_{CC} specification for $T_{PCB} \le 105^{\circ}C$ in Electrical Characteristics: LVPECL Output, at $V_{CC} = 3$ V to 3.6 V

Changes from Revision B (May 2010) to Revision C

•	Revised description of pin 8	3
•	Corrected VIL parameter description in <i>Electrical Characteristics</i> table for LVCMOS inputs	5
•	Added footnote (2) to <i>Electrical Characteristics</i> table for LVPECL Output, V _{CC} = 2.375 V to 2.625 V	6
•	Changed recommended resistor values in Figure 12(a)	. 13
•	Changed resistor values in Figure 16	15
•	Changed resistor values in Figure 17	15

2



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Page

Page

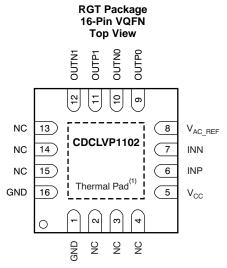


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5 Pin Configuration and Functions



(1) Thermal pad must be soldered to ground.

Pin Functions

PIN NAME NUMBER		ТҮРЕ	DESCRIPTION		
		ITPE			
GND	1, 16	Ground	Device ground		
INP, INN	6, 7	Input	Differential input pair or single-ended input		
OUTP1, OUTN1	11, 12	Output	Differential LVPECL output pair no. 1. Unused output pair can be left floating.		
OUTP0 OUTN0	9, 10	Output	Differential LVPECL output pair no. 0. Unused output pair can be left floating.		
V _{AC_REF}	8	Output	Bias voltage output for capacitive-coupled input pair no. 0. Do not use V_{AC_REF} at V_{CC} < 3.0 V. If used, it is recommended to use a 0.1-µF capacitor to GND on this pin. The output current is limited to 2 mA.		
V _{CC}	5	Power	2.5-V/3.3-V supply for the device		
NC	2, 3, 4, 13, 14, 15	—	Do not connect		



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _{CC}	Supply voltage range ⁽²⁾	-0.5	4.6	V
V _{IN}	Input voltage range (3)	-0.5	V _{CC} + 0.5	V
V _{OUT}	Output voltage range ⁽³⁾	-0.5	V _{CC} + 0.5	V
I _{IN}	Input current		20	mA
I _{OUT}	Output current		50	mA
T _A	Specified free-air temperature (no airflow)	-40	85	°C
TJ	Maximum junction temperature		125	°C
T _{stg}	Storage temperature	-65	150	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All supply voltages must be supplied simultaneously.

(3) The input and output negative voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

6.2 ESD Ratings

		VALUE	UNIT
V _(ESD) Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	2.375	2.50/3.30	3.60	V
T _A	Ambient temperature	-40		85	°C
T _{PCB}	PCB temperature (measured at thermal pad)			105	°C

6.4 Thermal Information

			CDCLVP1102	
	THERMAL METRIC ⁽¹⁾⁽²⁾⁽³⁾	RGT (VQFN)	UNIT	
		16 PINS		
		0 LFM ⁽⁴⁾	51.8	
$R_{\theta JA}$	Junction-to-ambient thermal resistance 150 LFM ⁽⁴⁾ 400 LFM ⁽⁴⁾	150 LFM ⁽⁴⁾	45	°C/W
		40.8		
R _{θJC(to}	Junction-to-case (top) thermal resistance	61.3	°C/W	
$R_{\theta JB}^{(5)}$	Junction-to-board thermal resistance	21.7	°C/W	
ΨJT	Junction-to-top characterization parameter	1.5	°C/W	
ψ_{JB}	Junction-to-board characterization parameter	21.7	°C/W	
R _{θJC(b} ot)	Junction-to-case (bottom) thermal resistance		6.3	°C/W

 For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report (SPRA953).

(2) The package thermal resistance is calculated in accordance with JESD 51 and JEDEC 2S2P (high-K board).

(3) Connected to GND with four thermal vias (0.3-mm diameter).

(4) 2 x 2 vias on Pad

(5) θ_{JP} (junction-to-pad) is used for the QFN package, because the primary heat flow is from the junction to the GND pad of the QFN package.

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6.5 Electrical Characteristics: LVCMOS Input

at V_{CC} = 2.375 V to 3.6 V and T_A = -40°C to 85°C and T_{PCB} ≤ 105°C (unless otherwise noted)⁽¹⁾

8	100 (,		
PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
Input frequency			200) MHz
Input threshold voltage	External threshold voltage applied to complementary input	1.1	1.8	3 V
Input high voltage		V _{th} + 0.1	V _{CC}	y V
Input low voltage		0	V _{th} - 0.1	V
Input high current	$V_{CC} = 3.6 \text{ V}, \text{ V}_{IH} = 3.6 \text{ V}$		40) μA
Input low current	$V_{CC} = 3.6 \text{ V}, \text{ V}_{IL} = 0 \text{ V}$		-40	μΑ
Input edge rate	20% to 80%	1.5		V/ns
Input capacitance			5	pF
	PARAMETER Input frequency Input threshold voltage Input high voltage Input low voltage Input high current Input low current Input low current Input edge rate	PARAMETERTEST CONDITIONSInput frequencyExternal threshold voltage applied to complementary inputInput threshold voltageInput high voltageInput low voltageInput low voltageInput high current $V_{CC} = 3.6 \text{ V}, \text{ V}_{IH} = 3.6 \text{ V}$ Input low current $V_{CC} = 3.6 \text{ V}, \text{ V}_{IL} = 0 \text{ V}$ Input edge rate20% to 80%	PARAMETERTEST CONDITIONSMINInput frequencyInput threshold voltageExternal threshold voltage applied to complementary input1.1Input high voltage $V_{th} + 0.1$ Input low voltage0Input high current $V_{CC} = 3.6 \text{ V}, \text{ V}_{IH} = 3.6 \text{ V}$ Input low current $V_{CC} = 3.6 \text{ V}, \text{ V}_{IL} = 0 \text{ V}$ Input edge rate20% to 80%1.5	PARAMETERTEST CONDITIONSMINTYPMAXInput frequency200Input threshold voltageExternal threshold voltage applied to complementary input1.11.8Input high voltageVth + 0.1VccInput low voltage0Vth - 0.1Input high currentVcc = 3.6 V, VIH = 3.6 V400Input low currentVcc = 3.6 V, VIL = 0 V-400Input edge rate20% to 80%1.5

(1) Figure 3 and Figure 4 show DC test setup.

6.6 Electrical Characteristics: Differential Input

at V_{CC} = 2.375 V to 3.6 V and T_A = -40°C to 85°C and T_{PCB} ≤ 105°C (unless otherwise noted)⁽¹⁾

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
f _{IN}	Input frequency	Clock input		2000	MHz
V	Differential input peak peak valtage	f _{IN} ≤ 1.5 GHz	0.1	1.5	V
V _{IN, DIFF, PP}	Differential input peak-peak voltage	1.5 GHz ≤ f _{IN} ≤ 2 GHz	0.2	1.5	V
V _{ICM}	Input common-mode level		1	V _{CC} – 0.3	V
I _{IH}	Input high current	$V_{CC} = 3.6 \text{ V}, \text{ V}_{IH} = 3.6 \text{ V}$		40	μA
IIL	Input low current	$V_{CC} = 3.6 \text{ V}, \text{ V}_{IL} = 0 \text{ V}$		-40	μA
$\Delta V / \Delta T$	Input edge rate	20% to 80%	1.5		V/ns
I _{CAP}	Input capacitance			5	pF

(1) Figure 5 and Figure 6 show DC test setup. Figure 7 shows AC test setup.

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6.7 Electrical Characteristics: LVPECL Output

at V_{CC} = 2.375 V to 2.625 V and T_A = -40°C to 85°C and T_{PCB} \leq 105°C (unless otherwise noted)⁽¹⁾

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
		T _A ≤ 85°C	V _{CC} – 1.26	V _{CC} – 0.9	V
V _{OH}	Output high voltage	T _{PCB} ≤ 105ºC	V _{CC} - 1.26	V _{CC} – 0.83	V
N/		T _A ≤ 85°C	V _{CC} – 1.7	V _{CC} – 1.3	V
V _{OL}	Output low voltage	T _{PCB} ≤ 105°C	V _{CC} – 1.7	V _{CC} – 1.25	V
V _{OUT, DIFF, PP}	Differential output peak-peak voltage	f _{IN} ≤ 2 GHz	0.5	1.35	V
V _{AC_REF}	Input bias voltage ⁽²⁾	$I_{AC_{REF}} = 2 \text{ mA}$	V _{CC} – 1.6	V _{CC} – 1.1	V
+	Propagation delay	$V_{IN, DIFF, PP} = 0.1 V$		450	ps
t _{PD}	Flopagation delay	$V_{IN, DIFF, PP} = 0.3 V$		450	ps
t _{SK,PP}	Part-to-part skew			100	ps
t _{SK,O}	Output skew			10	ps
t _{SK,P}	Pulse skew (with 50% duty cycle input)	Crossing-point-to-crossing-point distortion, f _{OUT} = 100 MHz	-50	50	ps
		f_{OUT} = 100 MHz, $V_{IN,SE}$ = V_{CC} , V_{th} = 1.25 V, 10 kHz to 20 MHz		0.089	ps, RMS
		f_{OUT} = 100 MHz, V _{IN,SE} = 0.9 V, V _{th} = 1.1 V, 10 kHz to 20 MHz		0.093	ps, RMS
t _{RJIT}	Random additive jitter (with 50% duty cycle input)	f_{OUT} = 2 GHz, $V_{IN,DIFF,PP}$ = 0.2 V, V_{ICM} = 1 V, 10 kHz to 20 MHz	, 0.037	0.037	ps, RMS
		$ \begin{array}{l} f_{OUT} = 100 \text{ MHz}, \text{V}_{\text{IN},\text{DIFF},\text{PP}} = 0.15 \\ \text{V}, \\ \text{V}_{\text{ICM}} = 1 \text{ V}, 10 \text{ kHz} \text{ to } 20 \text{ MHz} \end{array} $		0.094	ps, RMS
		f_{OUT} = 100 MHz, $V_{IN,DIFF,PP}$ = 1 V, V_{ICM} = 1 V, 10 kHz to 20 MHz		0.091	ps, RMS
t _R /t _F	Output rise/fall time	20% to 80%		200	ps
	Quantu internal current	Outputs unterminated, $T_A \le 85^{\circ}C$		33	mA
I _{EE}	Supply internal current	Outputs unterminated, $T_{PCB} \le 105^{\circ}C$		34	mA
1	Output and internal aunaly average	All outputs terminated, 50 Ω to V_{CC} – 2, $T_A \leq 85^{\circ}C$		100	mA
I _{CC}	Output and internal supply current	All outputs terminated, 50 Ω to $V_{CC} - 2$, $T_{PCB} \le 105^{\circ}C$	$T_A \le 85^{\circ}C$ $V_{CC} - 1.26$ $T_{PCB} \le 105^{\circ}C$ $V_{CC} - 1.7$ $T_{PCB} \le 105^{\circ}C$ $V_{CC} - 1.6$ DIFF, PP = 0.1 V DIFF, PP = 0.1 V DIFF, PP = 0.3 V -50 ssing-point-to-crossing-point ortion, $f_{OUT} = 100$ MHz -50 $= 100$ MHz, $V_{IN,SE} = V_{CC}$, $= 1.25 V, 10$ kHz to 20 MHz -50 $= = 100$ MHz, $V_{IN,SE} = 0.9$ V, $= 1.1$ V, 10 kHz to 20 MHz -50 $= = 2$ GHz, $V_{IN,DIFF,PP} = 0.2$ V, $A_1 = 1$ V, 10 kHz to 20 MHz -50 $= = 100$ MHz, $V_{IN,DIFF,PP} = 0.2$ V, $A_1 = 1$ V, 10 kHz to 20 MHz -100 MHz, $V_{IN,DIFF,PP} = 1$ V, $A_1 = 1$ V, 10 kHz to 20 MHz -100 MHz, $V_{IN,DIFF,PP} = 1$ V, $A_2 = 100$ MHz, $V_{IN,DIFF,PP} = 1$ V, $A_3 = 105^{\circ}C$ -2 , $= 85^{\circ}C$ -2 , $= 85^{\circ}C$ putputs terminated, 50 Ω to -2 , $= 85^{\circ}C$ -2 , $= 85^{\circ}C$ -2 , $= 85^{\circ}C$	105	mA

(1)

Figure 8 and Figure 9 show DC and AC test setup. Internally generated bias voltage (V_{AC_REF}) is for 3.3-V operation only. It is recommended to apply externally generated bias voltage for $V_{CC} < 3.0$ V. (2)

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6.8 Electrical Characteristics: LVPECL Output

at V_{CC} = 3.0 V to 3.6 V and T_A = -40° C to 85°C and T_{PCB} ≤ 105°C (unless otherwise noted)⁽¹⁾

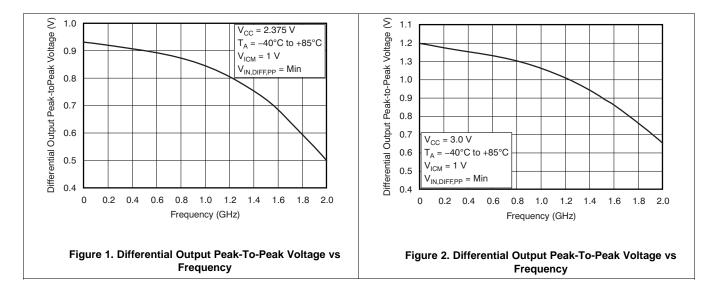
	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
\ <i>\</i>	O staat bisk aakta as	T _A ≤ 85°C	V _{CC} - 1.26	V _{CC} - 0.9	V
V _{OH}	Output high voltage	T _{PCB} ≤ 105°C	V _{CC} - 1.26	V _{CC} – 0.85	V
\ <i>\</i>		T _A ≤ 85°C	V _{CC} – 1.7	V _{CC} – 1.3	V
V _{OL}	Output low voltage	T _{PCB} ≤ 105°C	V _{CC} – 1.7	V _{CC} – 1.3	V
V _{OUT, DIFF, PP}	Differential output peak-peak voltage	f _{IN} ≤ 2 GHz	0.65	1.35	V
V _{AC_REF}	Input bias voltage	$I_{AC_REF} = 2 \text{ mA}$	V _{CC} – 1.6	V _{CC} – 1.1	V
t	Propagation delay	$V_{IN, DIFF, PP} = 0.1 V$		450	ps
t _{PD}	FT0pagation delay	$V_{IN, DIFF, PP} = 0.3 V$		450	ps
t _{SK,PP}	Part-to-part skew			100	ps
t _{SK,O}	Output skew			10	ps
t _{SK,P}	Pulse skew (with 50% duty cycle input)	Crossing-point-to-crossing-point distortion, $f_{OUT} = 100 \text{ MHz}$	-50	50	ps
		$\label{eq:four_output} \begin{array}{l} f_{OUT} = 100 \text{ MHz}, \text{V}_{\text{IN,SE}} = \text{V}_{\text{CC}}, \\ \text{V}_{\text{th}} = 1.65 \text{V}, 10 \text{kHz} \text{ to } 20 \text{MHz} \end{array}$		0.081	
		f_{OUT} = 100 MHz, $V_{IN,SE}$ = 0.9 V, V _{th} = 1.1 V, 10 kHz to 20 MHz		0.097	
t _{RJIT}	Random additive jitter (with 50% duty cycle input)	$f_{OUT} = 2 \text{ GHz}, V_{IN,DIFF,PP} = 0.2 \text{ V}, V_{ICM} = 1 \text{ V}, 10 \text{ kHz} \text{ to } 20 \text{ MHz}$		0.050	ps, RMS
		$ f_{OUT} = 100 \text{ MHz}, \text{V}_{\text{IN},\text{DIFF},\text{PP}} = 0.15 \\ \text{V}, \\ \text{V}_{\text{ICM}} = 1 \text{ V}, 10 \text{ kHz} \text{ to } 20 \text{ MHz} $		0.098	
		f_{OUT} = 100 MHz, $V_{IN,DIFF,PP}$ = 1 V, V_{ICM} = 1 V, 10 kHz to 20 MHz		0.095	
t _R /t _F	Output rise/fall time	20% to 80%		200	ps
	Currentu internet current	Outputs unterminated, $T_A \le 85^{\circ}C$		33	mA
I _{EE}	Supply internal current	Outputs unterminated, $T_{PCB} \le 105^{\circ}C$		34	mA
1		All outputs terminated, 50 Ω to V_{CC} – 2, $T_A \leq 85^{\circ}C$		100	mA
I _{CC}	Output and internal supply current	All outputs terminated, 50 Ω to V_{CC} – 2, T_{PCB} \leq 105°C		105	mA

(1) Figure 8 and Figure 9 show DC and AC test setup.



6.9 Typical Characteristics

at $T_A = -40^{\circ}$ C to 85°C (unless otherwise noted)



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7 Parameter Measurement Information

7.1 Test Configurations

This section describes the function of each block for the CDCLVP1102. Figure 3 through Figure 9 illustrate how the device should be setup for a variety of test configurations.

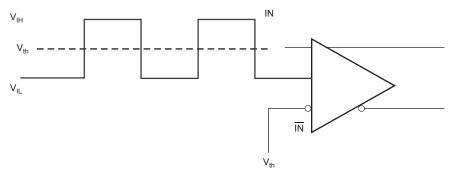


Figure 3. DC-Coupled LVCMOS Input During Device Test

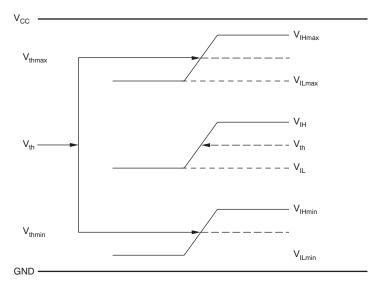


Figure 4. V_{th} Variation Over LVCMOS Levels

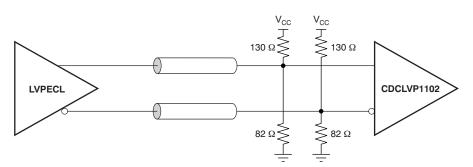


Figure 5. DC-Coupled LVPECL Input During Device Test



Test Configurations (continued)

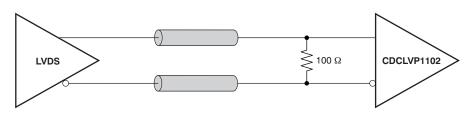


Figure 6. DC-Coupled LVDS Input During Device Test

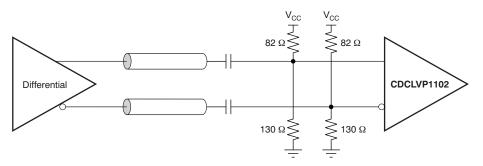


Figure 7. AC-Coupled Differential Input to Device

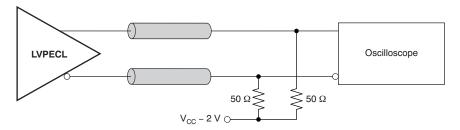


Figure 8. LVPECL Output DC Configuration During Device Test

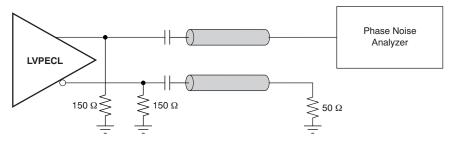


Figure 9. LVPECL Output AC Configuration During Device Test

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Test Configurations (continued)

Figure 10 shows the output voltage and rise/fall time. Output and part-to-part skew are shown in Figure 11.

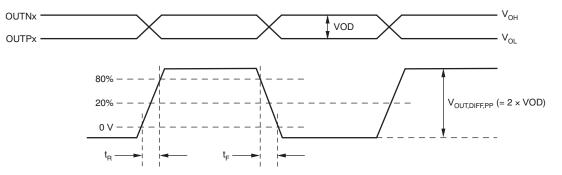
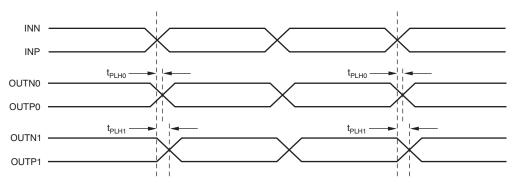


Figure 10. Output Voltage and Rise/Fall Time



- (1) Output skew is calculated as the greater of the following: As the difference between the fastest and the slowest t_{PLHn} (n = 0, 1), or as the difference between the fastest and the slowest t_{PHLn} (n = 0, 1).
- (2) Part-to-part skew is calculated as the greater of the following: As the difference between the fastest and the slowest t_{PLHn} (n = 0, 1) across multiple devices, or the difference between the fastest and the slowest t_{PHLn} (n = 0, 1) across multiple devices.

Figure 11. Output and Part-to-Part Skew

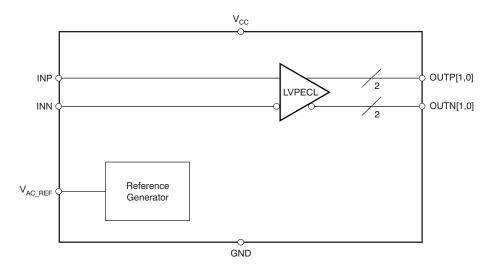


8 Detailed Description

8.1 Overview

The CDCLVP1102 is an open emitter for LVPECL outputs. Therefore, proper biasing and termination are required to ensure correct operation of the device and to minimize signal integrity. The proper termination for LVPECL outputs is 50 Ω to (V_{CC} –2) V, but this DC voltage is not readily available on PCB. Therefore, a Thevenin equivalent circuit is worked out for the LVPECL termination in both direct-coupled (DC) and AC coupled configurations. These configurations are shown in Figure 12 for V_{CC} = 2.5 V and Figure 13 for V_{CC} = 3.3 V, respectively. It is recommended to place all resistive components close to either the driver end or the receiver end. If the supply voltage for the driver and receiver is different, AC coupling is required.

8.2 Functional Block Diagram



8.3 Feature Description

The CDCLVP1102 is a low additive jitter universal to LVPECL fan out buffer with 2 outputs and 1 input. The small package, low output skew, and low additive jitter make for a flexible device in demanding applications.

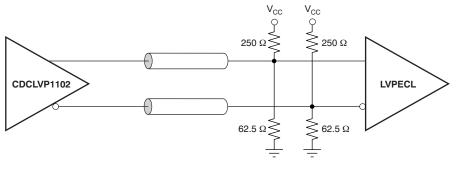
8.4 Device Functional Modes

The CDCLVP1102 is an open emitter for LVPECL outputs. Therefore, proper biasing and termination are required to ensure correct operation of the device and to minimize signal integrity. The proper termination for LVPECL outputs is 50 Ω to (V_{CC} –2) V, but this dc voltage is not readily available on PCB. Therefore, a Thevenin equivalent circuit is worked out for the LVPECL termination in both direct-coupled (DC) and AC-coupled configurations. These configurations are shown in Figure 12a and b for V_{CC} = 2.5 V and Figure 13a and b for V_{CC} = 3.3 V, respectively. It is recommended to place all resistive components close to either the driver end or the receiver end. If the supply voltage for the driver and receiver is different, ac coupling is required.

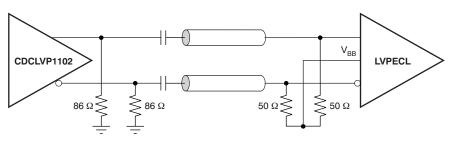


Device Functional Modes (continued)

8.4.1 LVPECL Output Termination



(a) Output DC Termination

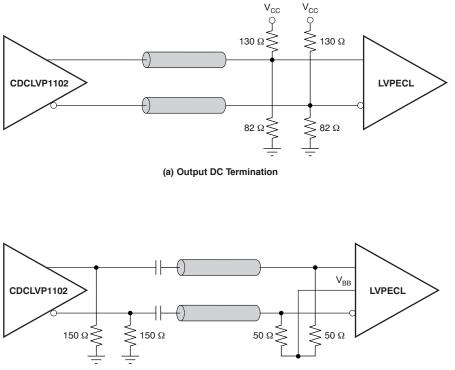


(b) Output AC Termination

Figure 12. LVPECL Output DC and AC Termination for V_{CC} = 2.5 V



Device Functional Modes (continued)



(b) Output AC Termination

Figure 13. LVPECL Output DC and AC Termination for V_{CC} = 3.3 V

8.4.2 Input Termination

The CDCLVP1102 inputs can be interfaced with LVPECL, LVDS, or LVCMOS drivers. Figure 14 illustrates how to dc couple an LVCMOS input to the CDCLVP1102. The series resistance (R_S) should be placed close to the LVCMOS driver; its value is calculated as the difference between the transmission line impedance and the driver output impedance.

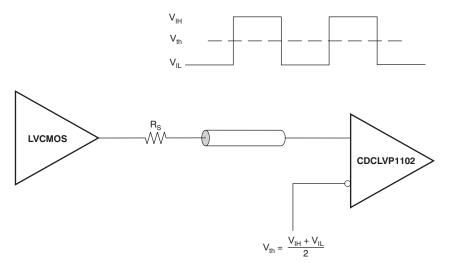


Figure 14. DC-Coupled LVCMOS Input to CDCLVP1102

Figure 15 shows how to dc couple LVDS inputs to the CDCLVP1102. Figure 16 and Figure 17 describe the method of dc coupling LVPECL inputs to the CDCLVP1102 for $V_{CC} = 2.5$ V and $V_{CC} = 3.3$ V, respectively.

Device Functional Modes (continued)

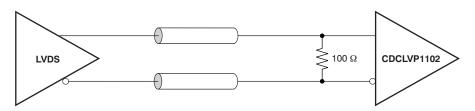


Figure 15. DC-Coupled LVDS Inputs to CDCLVP1102

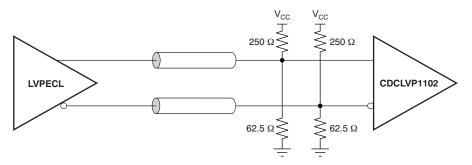


Figure 16. DC-Coupled LVPECL Inputs to CDCLVP1102 ($V_{CC} = 2.5 V$)

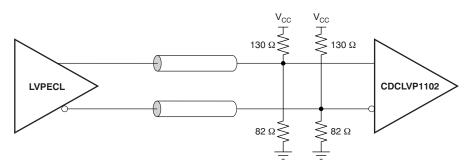


Figure 17. DC-Coupled LVPECL Inputs to CDCLVP1102 ($V_{CC} = 3.3 V$)

Figure 18 and Figure 19 show the technique of AC coupling differential inputs to the CDCLVP1102 for $V_{CC} = 2.5$ V and $V_{CC} = 3.3$ V, respectively. It is recommended to place all resistive components close to either the driver end or the receiver end. If the supply voltages of the driver and receiver are different, ac coupling is required.

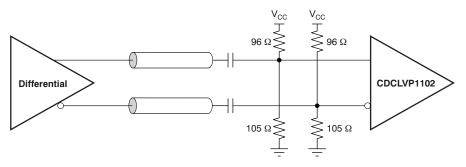


Figure 18. AC-Coupled Differential Inputs to CDCLVP1102 (V_{CC} = 2.5 V)



Device Functional Modes (continued)

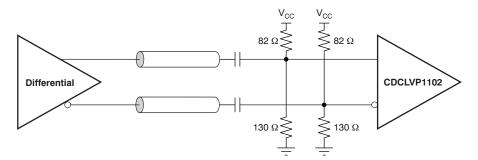


Figure 19. AC-Coupled Differential Inputs to CDCLVP1102 ($V_{CC} = 3.3 V$)



9 Application and Implementation

NOTE

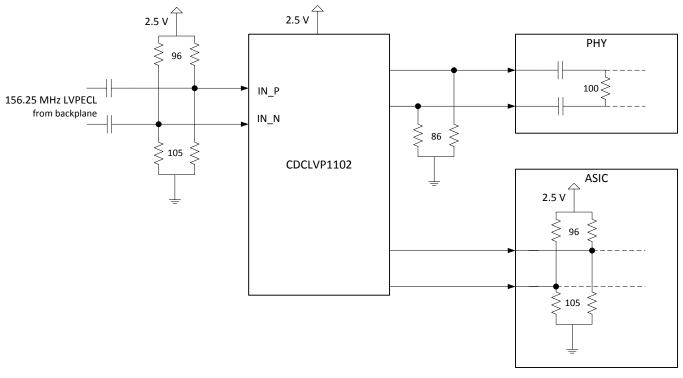
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

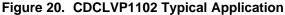
9.1 Application Information

The CDCLVP1102 is a low additive jitter LVPECL fanout buffer that can generate two copies of a LVPECL, LVDS, or LVCMOS input. The CDCLVP1102 can accept reference clock frequencies up to 2 GHz while providing low output skew.

9.2 Typical Application

9.2.1 Fanout Buffer for Line Card Application





9.2.1.1 Design Requirements

The CDCLVP1102 shown in Figure 20 is configured to receive a 156.25-MHz LVPECL clock from the backplane. Either signal can be then fanned out to desired devices, as shown. The configuration example is driving 2 LVPECL receivers in a line card application with the following properties:

- The PHY device has internal AC coupling and appropriate termination and biasing. The CDCLVP1102 will need to be provided with 86-Ω emitter resistors near the driver for proper operation.
- The ASIC is capable of DC coupling with a 2.5-V LVPECL driver such as the CDCLVP1102. This ASIC features internal termination so no additional components are needed.



Typical Application (continued)

9.2.1.2 Detailed Design Procedure

Refer to Input Termination for proper input terminations, dependent on single ended or differential inputs.

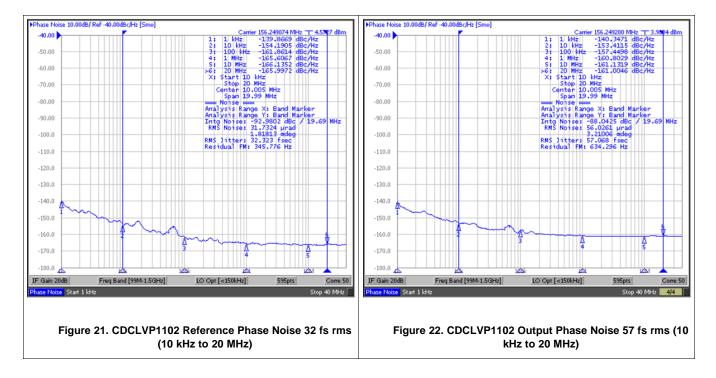
Refer to *LVPECL Output Termination* for output termination schemes depending on the receiver application. Unused outputs can be left floating.

In this example, the PHY, ASIC, and FPGA/CPU require different schemes. Power supply filtering and bypassing is critical for low noise applications.

See *Power Supply Recommendations* for recommended filtering techniques. A reference layout is provided on the CDCLVP1102 Evaluation Module at SCAU035.

9.2.1.3 Application Curves

The CDCLVP1102's low additive noise can be shown in this line card application. The low noise 156.25 MHz XO with 32-fs RMS jitter drives the CDCLVP1102, resulting in 57-fs RMS when integrated from 10 kHz to 20 MHz. The resultant additive jitter is a low 47-fs RMS for this configuration.





10 Power Supply Recommendations

High-performance clock buffers are sensitive to noise on the power supply, which can dramatically increase the additive jitter of the buffer. Thus, it is essential to reduce noise from the system power supply, especially when jitter/phase noise is very critical to applications.

Filter capacitors are used to eliminate the low-frequency noise from the power supply, where the bypass capacitors provide the very low impedance path for high-frequency noise and guard the power-supply system against the induced fluctuations. These bypass capacitors also provide instantaneous current surges as required by the device and should have low equivalent series resistance (ESR). To properly use the bypass capacitors, they must be placed very close to the power-supply pins and laid out with short loops to minimize inductance. It is recommended to add as many high-frequency (for example, 0.1-µF) bypass capacitors as there are supply pins in the package. It is recommended, but not required, to insert a ferrite bead between the board power supply and the chip power supply that isolates the high-frequency switching noises generated by the clock driver; these beads prevent the switching noise from leaking into the board supply. Choose an appropriate ferrite bead with very low dc resistance because it is imperative to provide adequate isolation between the board supply and the chip supply, as well as to maintain a voltage at the supply pins that is greater than the minimum voltage required for proper operation.

Figure 23 illustrates this recommended power-supply decoupling method.

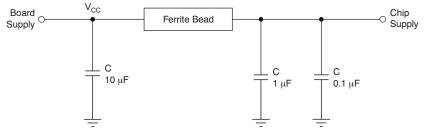


Figure 23. Power-Supply Decoupling



11 Layout

11.1 Layout Guidelines

Power consumption of the CDCLVP1102 can be high enough to require attention to thermal management. For reliability and performance reasons, the die temperature should be limited to a maximum of 125°C. That is, as an estimate, ambient temperature (T_A) plus device power consumption times $R_{\theta JA}$ should not exceed 125°C.

The device package has an exposed pad that provides the primary heat removal path to the printed circuit board (PCB). To maximize the heat dissipation from the package, a thermal landing pattern including multiple vias to a ground plane must be incorporated into the PCB within the footprint of the package. The exposed pad must be soldered down to ensure adequate heat conduction out of the package. Figure 24 shows a recommended land and via pattern.

11.2 Layout Example

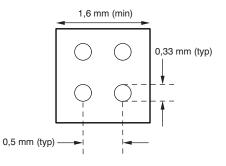


Figure 24. Recommended PCB Layout

11.3 Thermal Considerations

The CDCLVP1102 supports high temperatures on the printed circuit board (PCB) measured at the thermal pad. The system designer needs to ensure that the maximum junction temperature is not exceeded. Ψ_{jb} can allow the system designer to measure the board temperature with a fine gauge thermocouple and back calculate the junction temperature using Equation 1. Note that Ψ_{jb} is close to R_{0JB} as 75 to 95% of a device's heat is dissipated by the PCB. Further information can be found at SPRA953 and SLUA566.

 $T_{junction} = T_{PCB} + (\Psi_{jb} \times Power)$

(1)

Example:

Calculation of the junction-lead temperature with a 4-layer JEDEC test board using four thermal vias:

 $T_{PCB} = 105 \ ^{\circ}C$

 $\Psi_{ib} = 21.7 \text{ °C/W}$

Power_{inclTerm} = $I_{max} \times V_{max}$ = 105 mA × 3.6 V = 378 mW (max power consumption including termination resistors)

Power_{exclTerm} = 302.5 mW (max power consumption excluding termination resistors, see SLYT127 for further details)

 $\Delta T_{Junction} = \Psi_{jb} \times Power_{exclTerm} = 21.7 \text{ °C/W} \times 302.5 \text{ mW} = 6.56 \text{ °C}$

 $T_{Junction} = \Delta T_{Junction} + T_{Chassis} = 6.56$ °C + 105 °C = 111.56 °C (the maximum junction temperature of 125 °C is not violated)

TEXAS INSTRUMENTS

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12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For additional information, see the following:

- Using Thermal Calculation Tools for Analog Components (SLUA566)
- CDCLVP1102 Evaluation Module (SCAU035)
- Power Consumption of LVPECL and LVDS (SLYT127)

12.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E[™] Online Community *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support TI's Design Support Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.3 Trademarks

E2E is a trademark of Texas Instruments. All other trademarks are the property of their respective owners.

12.4 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



11-Aug-2017

PACKAGING INFORMATION

Orderable Device	Status	Package Type	•	Pins	•	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CDCLVP1102RGTR	ACTIVE	VQFN	RGT	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	1102	Samples
CDCLVP1102RGTT	ACTIVE	VQFN	RGT	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	1102	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

11-Aug-2017

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*	All dimensions are nominal												
	Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
	CDCLVP1102RGTR	VQFN	RGT	16	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
	CDCLVP1102RGTT	VQFN	RGT	16	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

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PACKAGE MATERIALS INFORMATION

11-Aug-2017



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCLVP1102RGTR	VQFN	RGT	16	3000	336.6	336.6	28.6
CDCLVP1102RGTT	VQFN	RGT	16	250	210.0	185.0	35.0

GENERIC PACKAGE VIEW

VQFN - 1 mm max height PLASTIC QUAD FLATPACK - NO LEAD



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



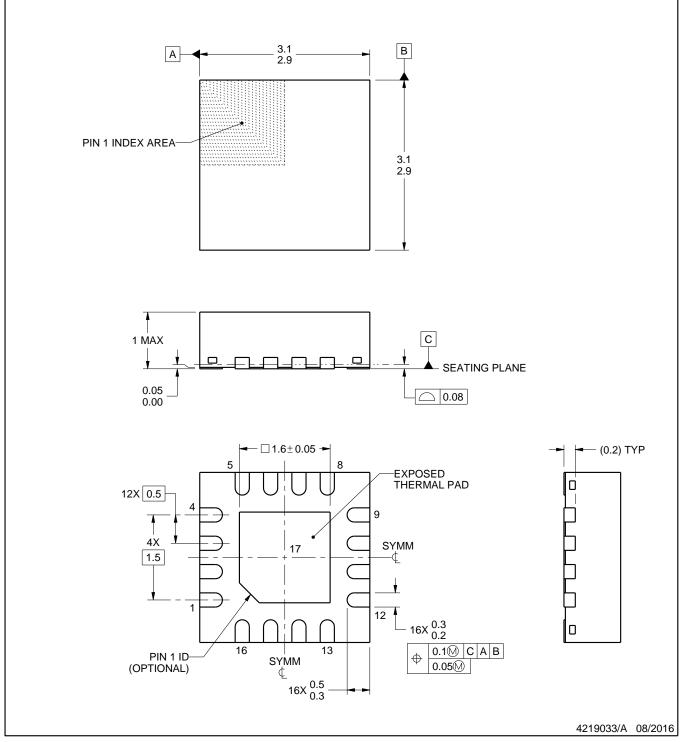
RGT0016B



PACKAGE OUTLINE

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

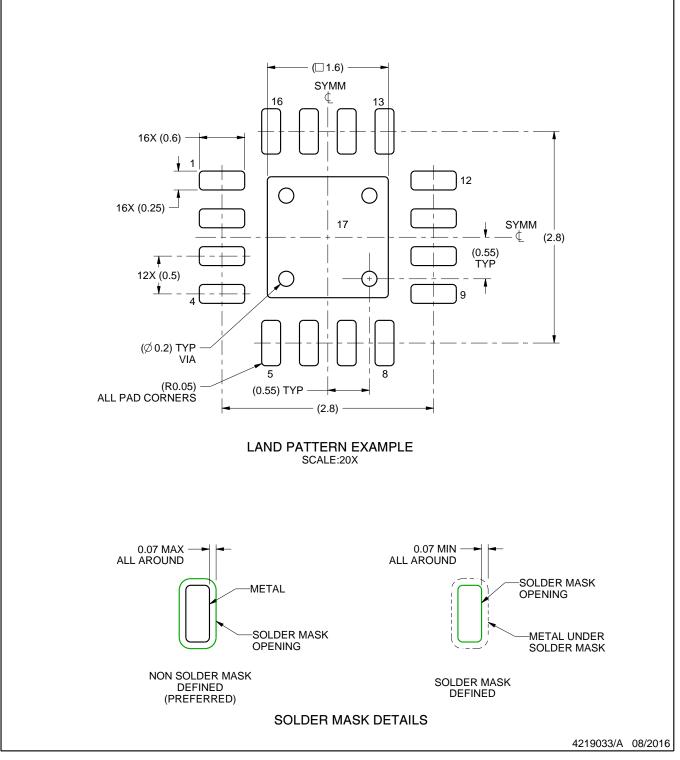


RGT0016B

EXAMPLE BOARD LAYOUT

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

 Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

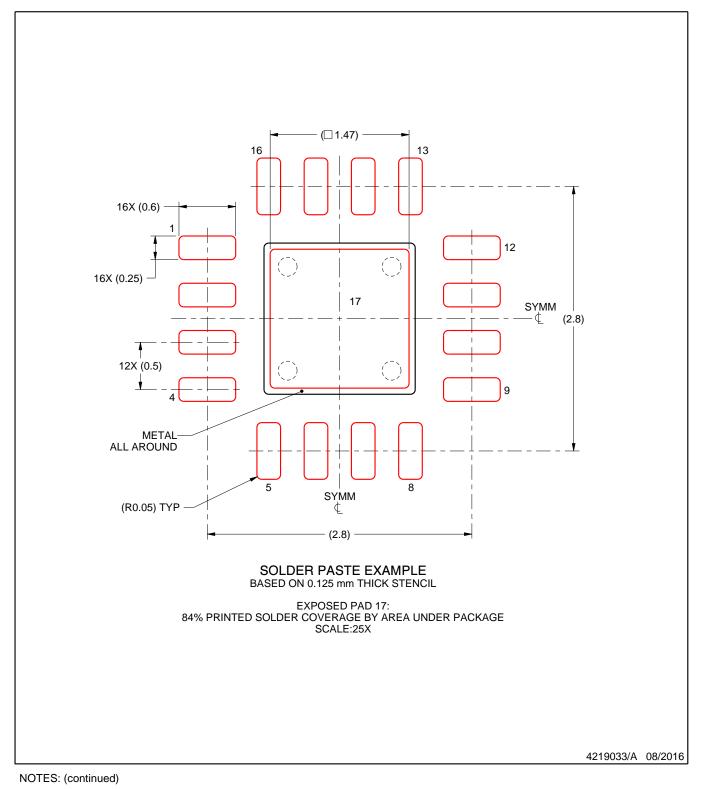


RGT0016B

EXAMPLE STENCIL DESIGN

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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